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PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Jeffrey T. Fanton et al.

Application No.: 10/053,373

Filed: October 24, 2001

For: X-RAY REFLECTANCE
MEASUREMENT SYSTEM WITH
ADJUSTABLE RESOLUTION

Confirmation No.: 2873

Group Art Unit: 2882

Examiner: I. Kiknadze

SUBMISSION OF FORMAL DRAWINGS

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CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope, addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on March 24, 2004.

STALLMAN & POLLOCK LLP

Dated: 03/24/2004

By:

Georgia K. Smith

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Sir:

In response to the Notice of Allowance and Issue Fee(s) Due mailed January 27, 2004, enclosed are six (6) sheets of formal replacement drawings for filing in the above-referenced application.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Dated: March 24, 2004

By: Michael A. Stallman

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Atty Docket No.: TWI-13310